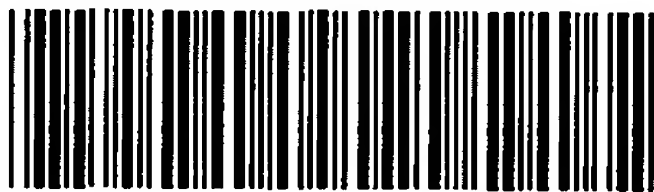


# Search Notes



Application/Control No.

10/624,506

Examiner

Edward Wojciechowicz

Applicant(s)/Patent under Reexamination

BYEON ET AL.

Art Unit

2815

## SEARCHED

Class	Subclass	Date	Examiner
257	328, 341 390, 401	11-5-06	EJH

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
CLAIMS IN PG-PUB		11-5-06	EJH

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
See search notes	11-5-06	EJH